

Description

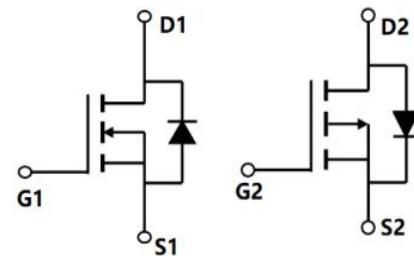
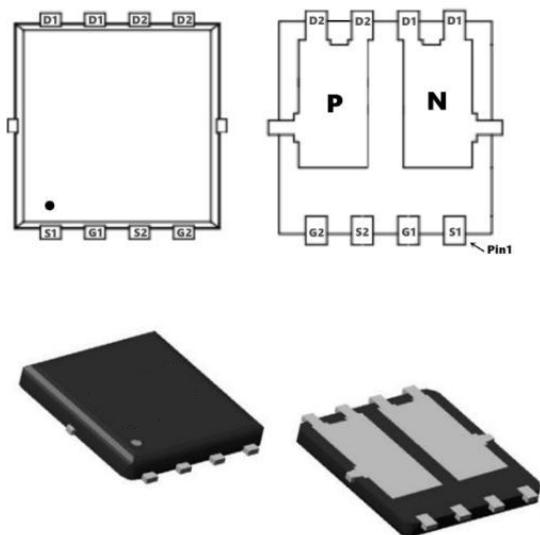
The SX10G06NFuses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 60V$ $I_D = 10A$
 $R_{DS(ON)} < 40m\Omega$ @ $V_{GS}=10V$
 $V_{DS} = -60V$ $I_D = -9.5A$
 $R_{DS(ON)} < 70m\Omega$ @ $V_{GS}=10V$

Application

Battery protection
Load switch
Uninterruptible power supply



Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating		Units
		N-Channel	P-Channel	
V_{DS}	Drain-Source Voltage	60	-60	V
V_{GS}	Gate-Source Voltage	± 20	± 20	V
$I_D@T_A=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	10	-9.5	A
$I_D@T_A=70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	5.2	-4.3	A
IDM	Pulsed Drain Current ²	30	-27	A
EAS	Single Pulse Avalanche Energy ³	25.5	35.3	mJ
IAS	Avalanche Current	22.6	-26.6	A
$P_D@T_A=25^\circ C$	Total Power Dissipation ⁴	1.5	1.5	W
TSTG	Storage Temperature Range	-55 to 150	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	85	85	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	36	36	°C/W

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	60	66	---	V
△BVDSS/△TJ	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =1mA	---	0.063	---	V/°C
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =4A	---	35	40	mΩ
		V _{GS} =4.5V , I _D =2A	---	38	45	
VGS(th)	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	1.2	1.6	2.5	V
V _{GS(th)}	V _{GS(th)} Temperature Coefficient		---	-5.24	---	mV/°C
IDSS	Drain-Source Leakage Current	V _{DS} =48V , V _{GS} =0V , T _J =25°C	---	---	1	uA
		V _{DS} =48V , V _{GS} =0V , T _J =55°C	---	---	5	
IGSS	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V	---	---	±100	nA
gfs	Forward Transconductance	V _{DS} =5V , I _D =4A	---	21	---	S
R _g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz	---	3.2	---	Ω
Q _g	Total Gate Charge (4.5V)	V _{DS} =48V , V _{GS} =4.5V , I _D =4A	---	12.6	---	nC
Q _{gs}	Gate-Source Charge		---	3.2	---	
Q _{gd}	Gate-Drain Charge		---	6.3	---	
Td(on)	Turn-On Delay Time	V _{DD} =30V , V _{GS} =10V , R _G =3.3Ω, I _D =4A	---	8	---	ns
T _r	Rise Time		---	14.2	---	
Td(off)	Turn-Off Delay Time		---	24.4	---	
T _f	Fall Time		---	4.6	---	
C _{iss}	Input Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz	---	1378	---	pF
C _{oss}	Output Capacitance		---	86	---	
C _{rss}	Reverse Transfer Capacitance		---	64	---	
I _S	Continuous Source Current ^{1.5}	V _G =V _D =0V , Force Current	---	---	4.8	A
ISM	Pulsed Source Current ^{2.5}		---	---	9.6	A
VSD	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T _J =25°C	---	---	1.2	V

Note :

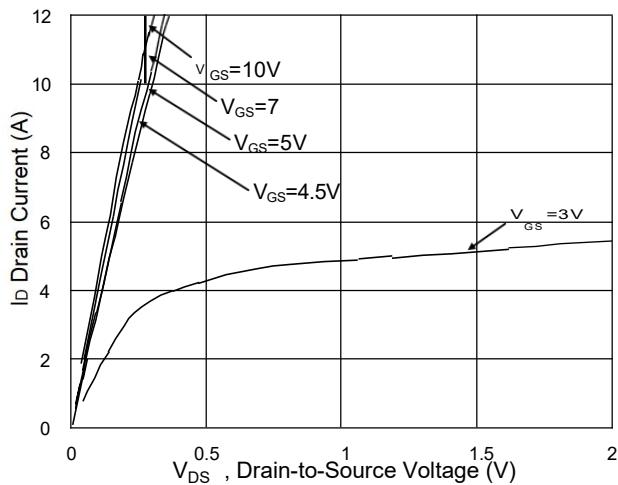
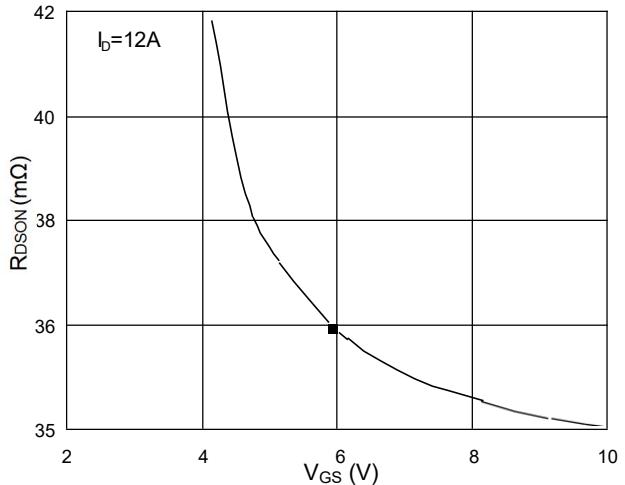
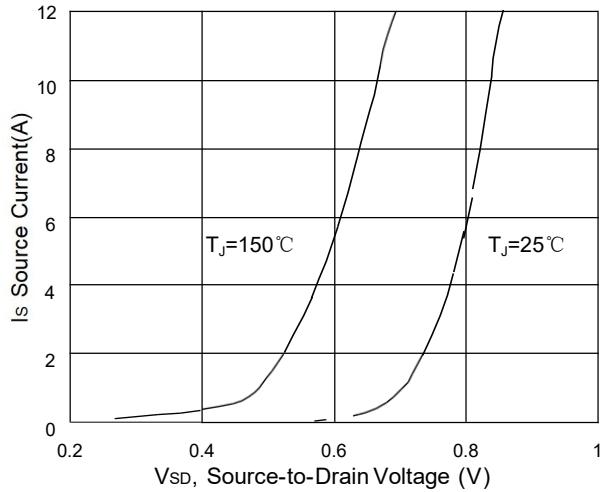
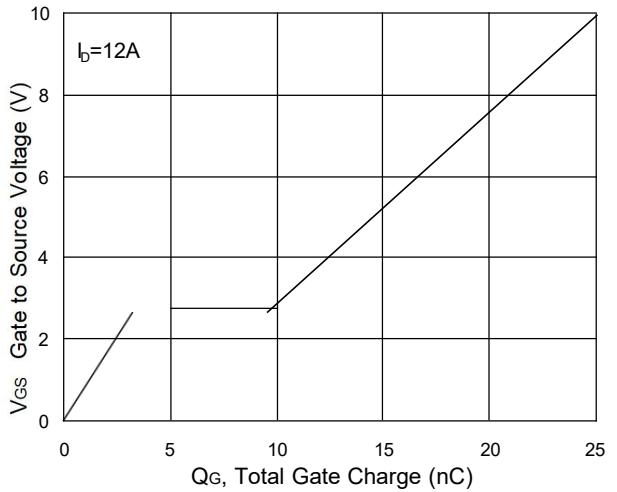
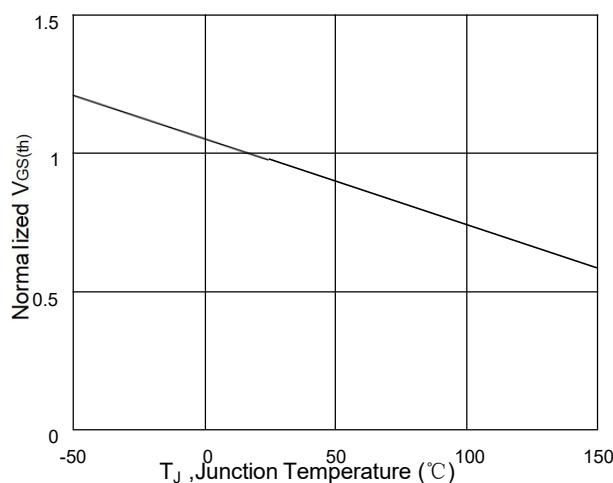
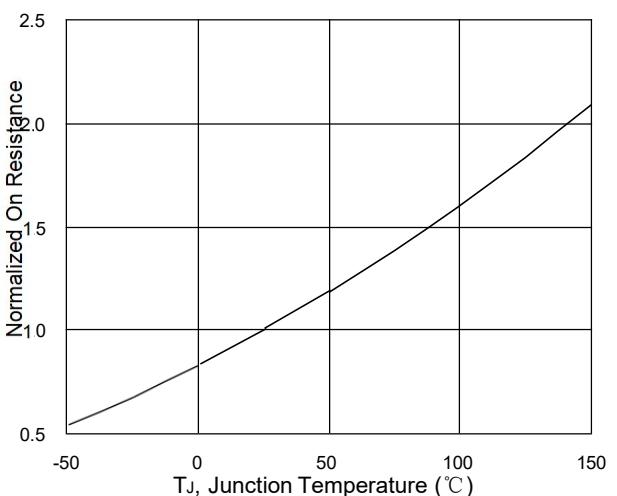
- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%
- 3.The EAS data shows Max. rating . The test condition is V_{DD}=-25V,V_{GS}=-10V,L=0.1mH,I_{AS}=-26.6A
- 4.The power dissipation is limited by 150 °C junction temperature
- 5.The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation

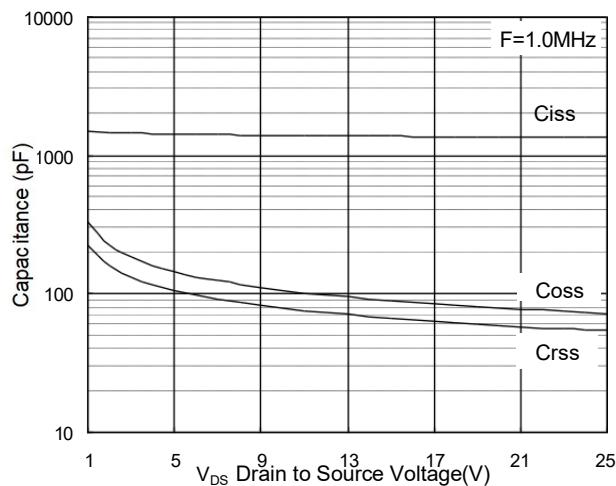
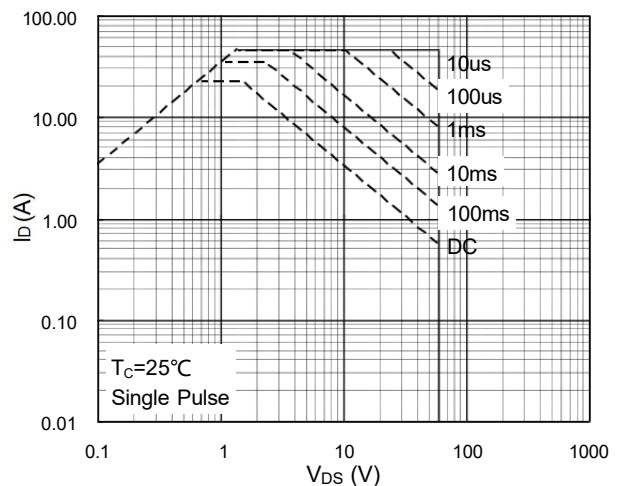
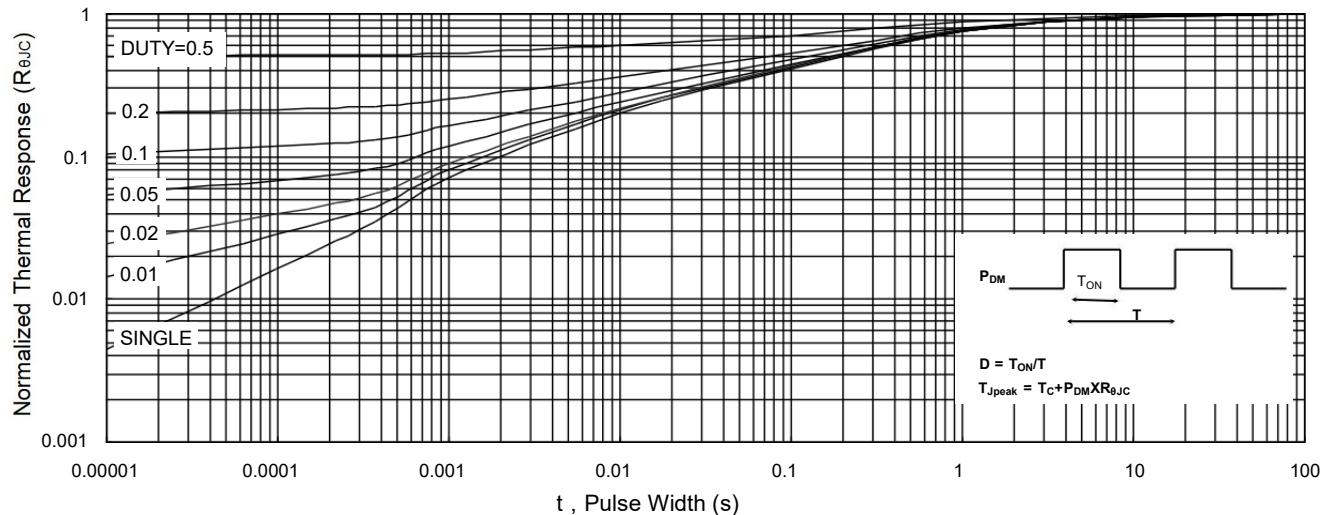
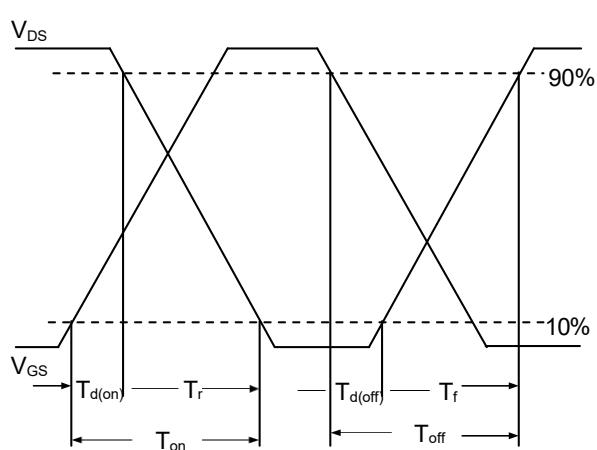
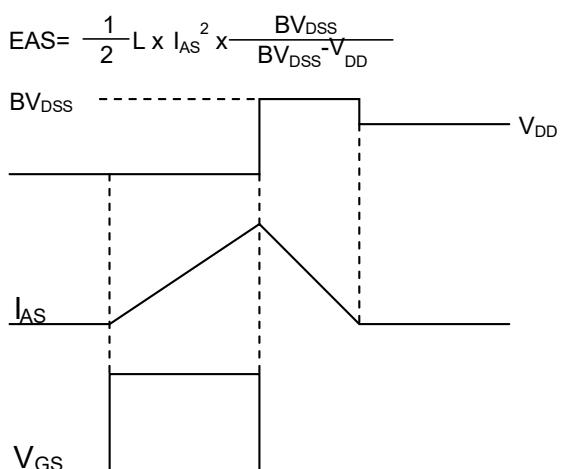
Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=-250\mu\text{A}$	-60	-66	---	V
$\Delta BVDSS/\Delta T_J$	$BVDSS$ Temperature Coefficient	Reference to 25°C , $I_D=-1\text{mA}$	---	-0.03	---	$\text{V}/^\circ\text{C}$
RDS(ON)	Static Drain-Source On-Resistance ²	$V_{GS}=-10\text{V}$, $I_D=-3\text{A}$	---	55	70	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}$, $I_D=-2\text{A}$	---	75	105	
VGS(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=-250\mu\text{A}$	-1.2	-1.5	-2.5	V
$V_{GS(\text{th})}$	$V_{GS(\text{th})}$ Temperature Coefficient		---	4.56	---	$\text{mV}/^\circ\text{C}$
IDSS	Drain-Source Leakage Current	$V_{DS}=-48\text{V}$, $V_{GS}=0\text{V}$, $T_J=25^\circ\text{C}$	---	---	1	μA
		$V_{DS}=-48\text{V}$, $V_{GS}=0\text{V}$, $T_J=55^\circ\text{C}$	---	---	5	
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm20\text{V}$, $V_{DS}=0\text{V}$	---	---	±100	nA
gfs	Forward Transconductance	$V_{DS}=-5\text{V}$, $I_D=-3\text{A}$	---	15	---	S
R _g	Gate Resistance	$V_{DS}=0\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	13.5	---	Ω
Q _g	Total Gate Charge (-4.5V)	$V_{DS}=-48\text{V}$, $V_{GS}=-4.5\text{V}$, $I_D=-3\text{A}$	---	9.86	---	nC
Qgs	Gate-Source Charge		---	3.1	---	
Qgd	Gate-Drain Charge		---	2.95	---	
Td(on)	Turn-On Delay Time	$V_{DD}=-15\text{V}$, $V_{GS}=-10\text{V}$, $R_G=3.3\Omega$, $I_D=-1\text{A}$	---	28.8	---	ns
T _r	Rise Time		---	19.8	---	
Td(off)	Turn-Off Delay Time		---	60.8	---	
T _f	Fall Time		---	7.2	---	
Ciss	Input Capacitance	$V_{DS}=-15\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	1447	---	pF
Coss	Output Capacitance		---	97.3	---	
Crss	Reverse Transfer Capacitance		---	70	---	
IS	Continuous Source Current ^{1,5}	$V_G=V_D=0\text{V}$, Force Current	---	---	-3.7	A
ISM	Pulsed Source Current ^{2,5}		---	---	-7.5	A
VSD	Diode Forward Voltage ²	$V_{GS}=0\text{V}$, $I_S=-1\text{A}$, $T_J=25^\circ\text{C}$	---	---	-1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $VDD=25\text{V}$, $VGS=10\text{V}$, $L=0.1\text{mH}$, $IAS=22.6\text{A}$
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation

N-Channel Typical Characteristics**Fig.1 Typical Output Characteristics****Fig.2 On-Resistance v.s Gate-Source****Fig.3 Forward Characteristics of Reverse****Fig.4 Gate-Charge Characteristics****Fig.5 Normalized $V_{GS(th)}$ v.s T_J** **Fig.6 Normalized R_{DSON} v.s T_J**

N-Channel Typical Characteristics**Fig.7 Capacitance****Fig.8 Safe Operating Area****Fig.9 Normalized Maximum Transient Thermal Impedance****Fig.10 Switching Time Waveform****Fig.11 Unclamped Inductive Waveform**

P-Channel Typical Characteristics

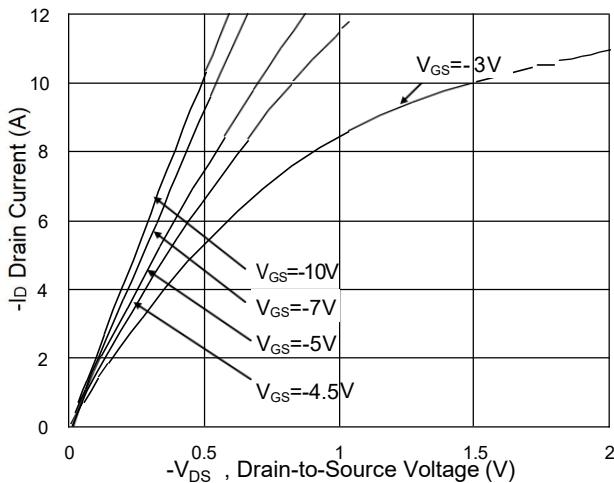


Fig.1 Typical Output Characteristics

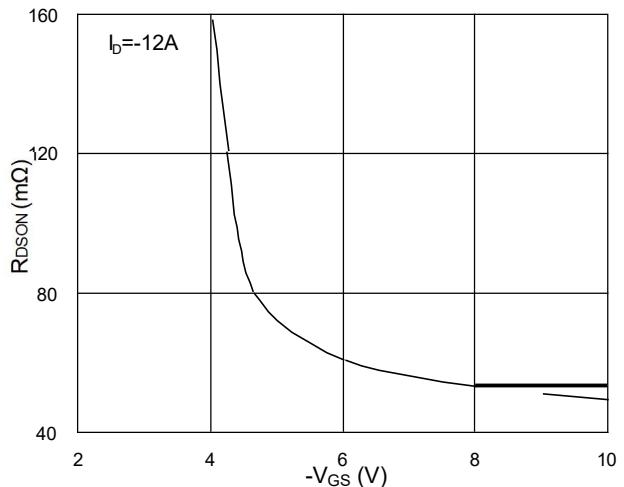


Fig.2 On-Resistance v.s Gate-Source

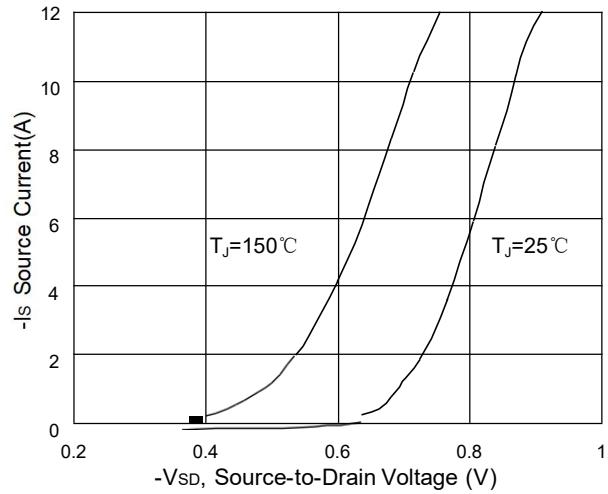


Fig.3 Forward Characteristics of Reverse

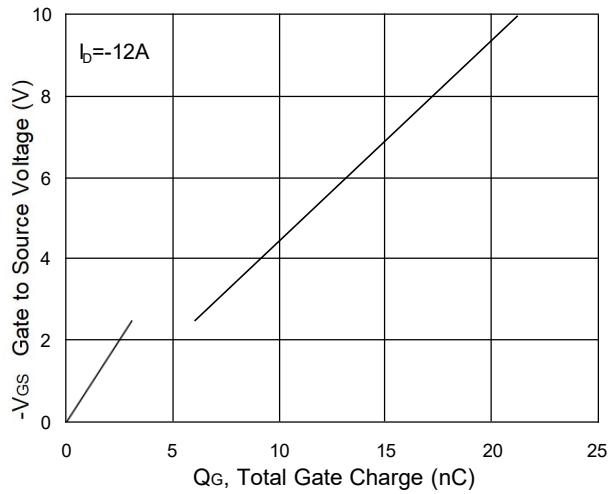


Fig.4 Gate-Charge Characteristics

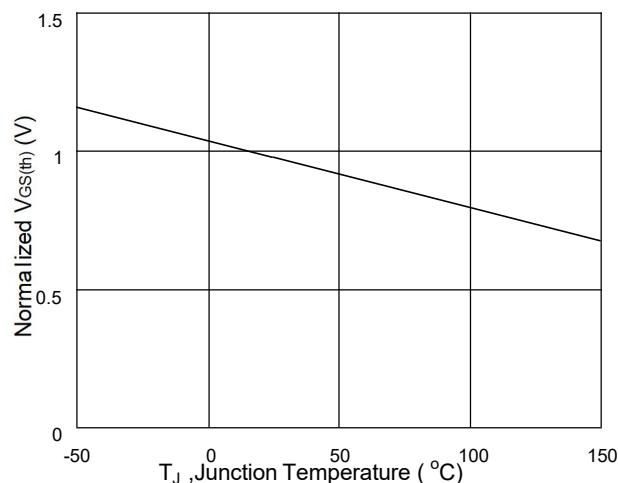


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

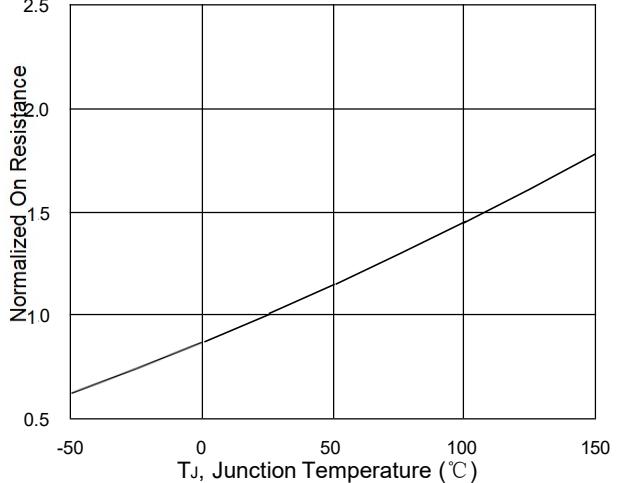
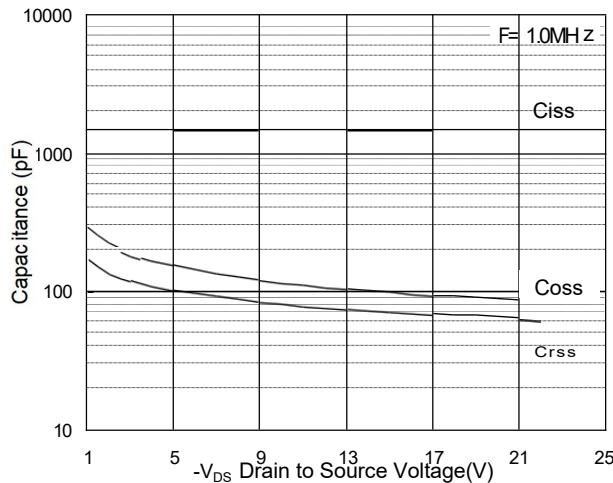
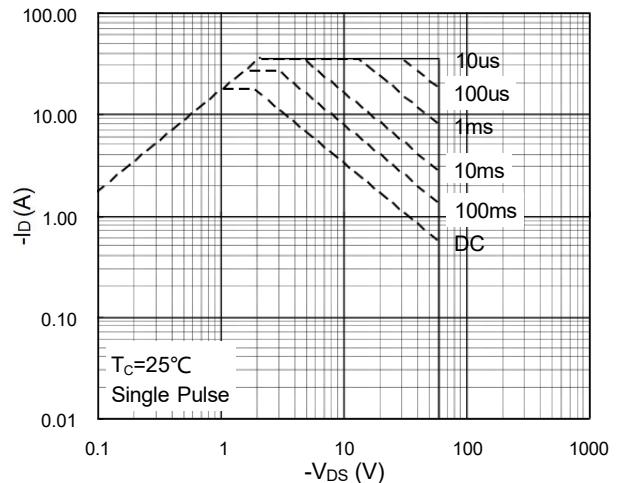
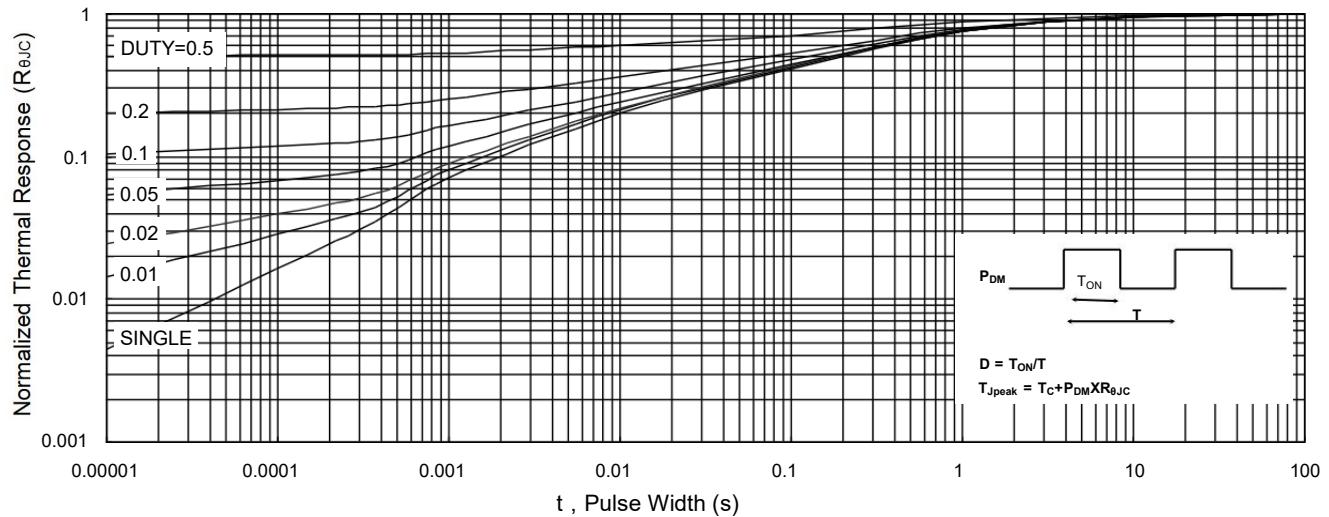
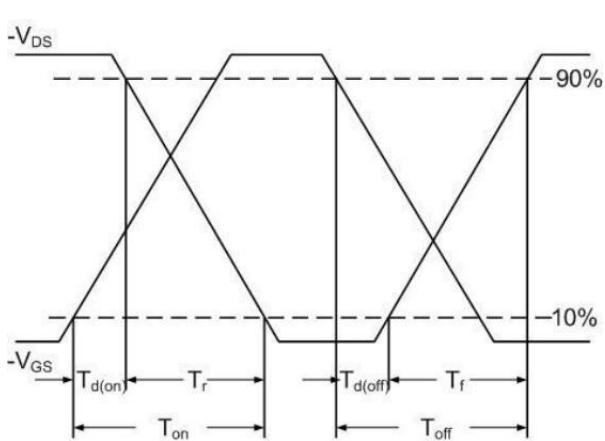
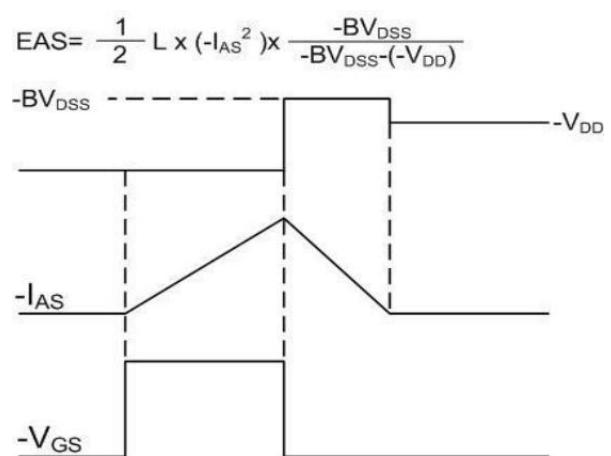
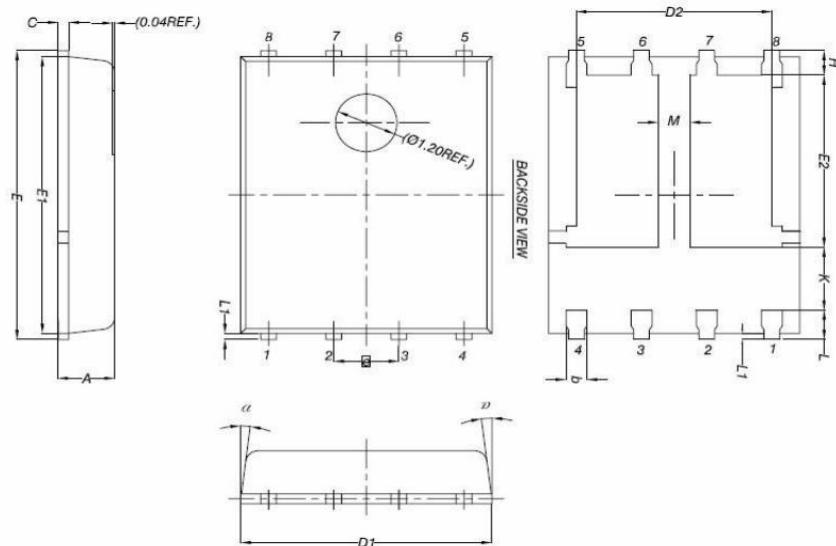


Fig.6 Normalized R_{DSON} v.s T_J

P-Channel Typical Characteristics**Fig.7 Capacitance****Fig.8 Safe Operating Area****Fig.9 Normalized Maximum Transient Thermal Impedance****Fig.10 Switching Time Waveform****Fig.11 Unclamped Inductive Waveform**

MOSFET Package Mechanical Data- PDFN5*6-8L-JQ Double



Symbol	Common mm		
	Mim	Nom	Max
A	0.90	1.00	1.10
b	0.33	0.41	0.51
C	0.20	0.25	0.30
D1	4.80	4.90	5.00
D2	3.61	3.81	3.96
E	5.90	6.00	6.10
E1	5.66	5.76	5.83
E2	3.37	3.47	3.58
e	1.27BSC		
H	0.41	0.51	0.61
K	1.10	--	--
L	0.51	0.61	0.71
L1	0.06	0.13	0.20
M	0.50	--	--
a	0 °	--	12 °

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
TAPING	PDFN5*6-8L		5000